

LECTURE 4: FORCE-DISTANCE CURVES

Outline :

LAST TIME : ADDITIONAL NANOMECHANICS INSTRUMENTATION COMPONENTS.....	2
PIEZOS TUBES : X/Y SCANNING	3
GENERAL COMPONENTS OF A NANOMECHANICAL DEVICE.....	4
HIGH RESOLUTION FORCE SPECTROSCOPY (HRFS)	5-9
<i>Force-Distance Raw Data</i>	5
<i>Force-Distance Data Conversion</i>	6
<i>Chemical Force Microscopy (CFM)</i>	7
<i>Macromolecular Adhesion : Cartilage Aggrecan</i>	8
<i>Lateral Force Microscopy (LFM)</i>	9

Objectives: To understand high resolution force spectroscopy data; i.e. how it is converted from raw data, interpretation of different regions, and different types (i.e. normal, lateral, & chemically specific)

Readings: Course Reader Document 10-11.

Multimedia : Watch movie *Introduction to AFM* by Asylum Research, Inc., and the Force curve animation from NCState.

LAST TIME : ADDITIONAL NANOMECHANICS INSTRUMENTATION COMPONENTS

High resolution displacement detection : Optical Lever (Beam) Deflection Technique

High resolution displacement control : "piezoelectric materials" : material which exhibits a change in dimensions in response to an applied voltage due to dipole alignment

ϵ is linearly proportional to electric field strength :

$$\epsilon_j = d_{ij} E_i$$

$$\epsilon_j = \frac{\Delta L}{L_0} = \text{strain (m/m = unitless)}$$

d_{ij} = strain coefficients or sensitivity (m/Volt)

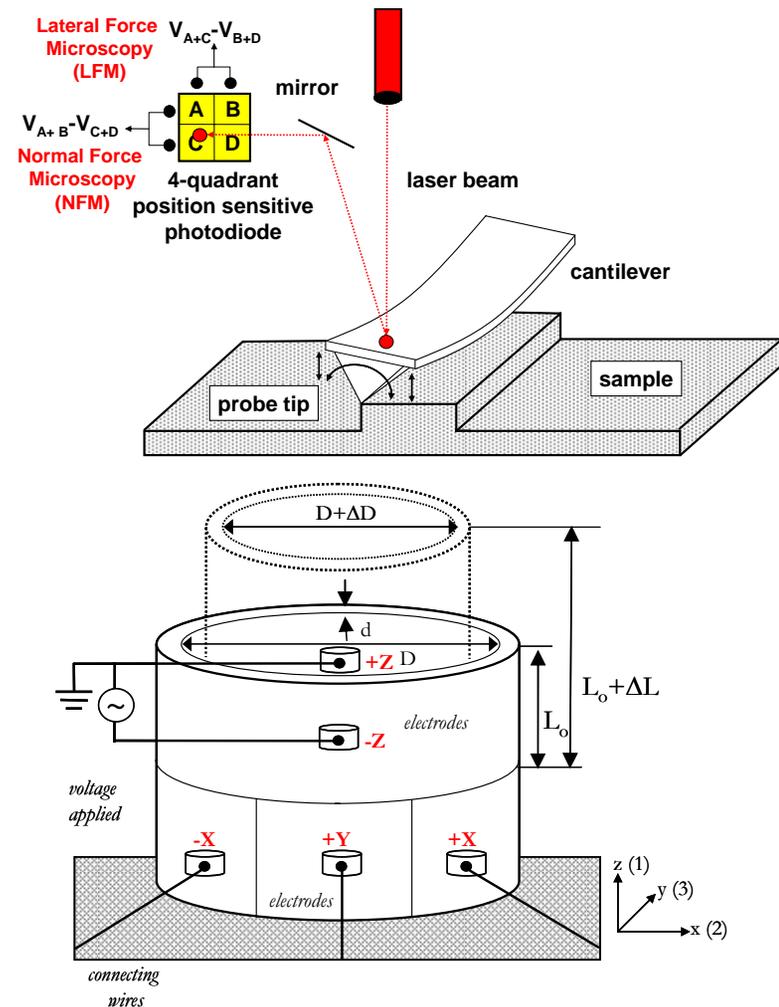
E_i = electric field strength (Volt/m)

i = direction of applied field, j = direction of strain

1,2,3 = normal axes ; 4,5,6 = shear

+ Poisson's ratio

$$\Delta L = \frac{L_0 d_{31} U_3}{d} \text{ where } d = \text{wall thickness, } U = \text{operating voltage}$$



PIEZO TUBES X/Y SCANNING

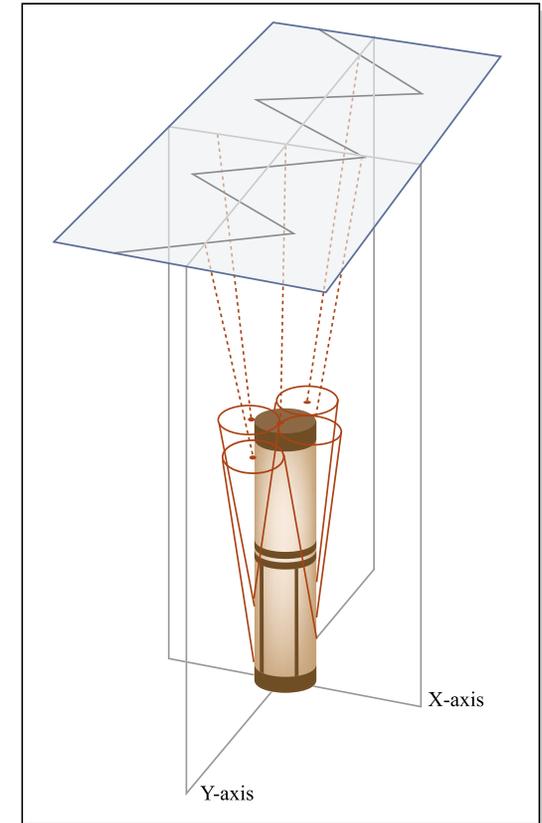
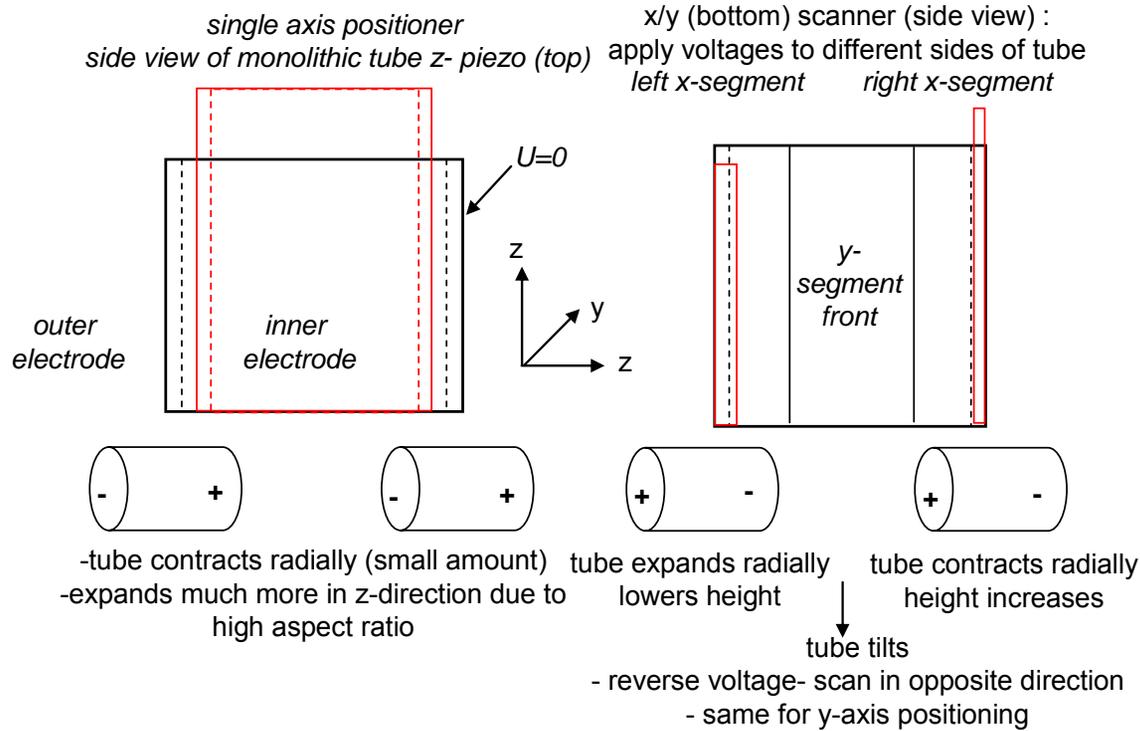
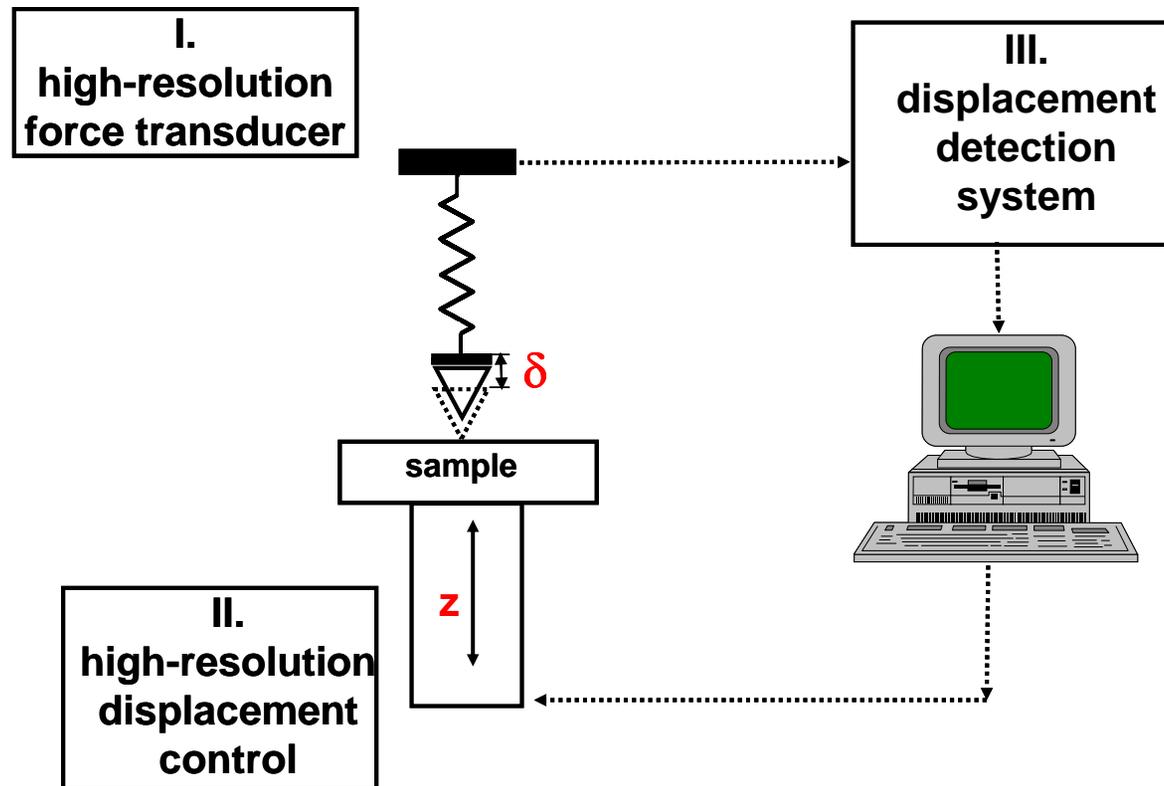


Figure by MIT OCW.

-Coupling - if you tell the piezo tube to move in x-direction, it will also move a bit in y and z, x is coupled to y and z

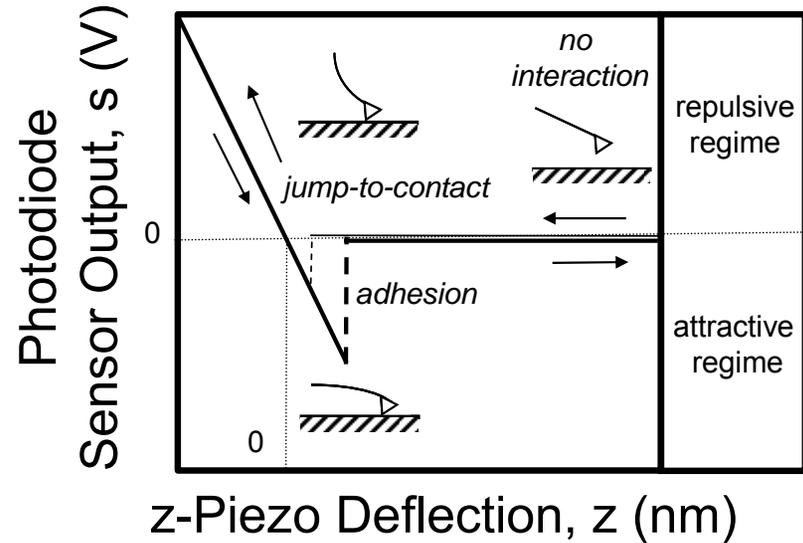
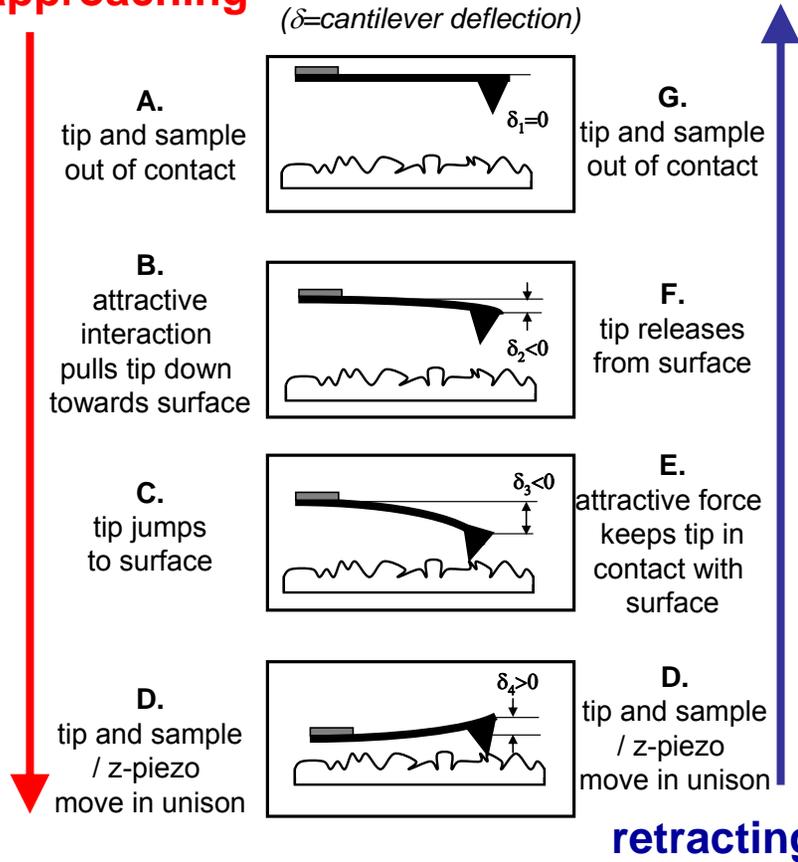
-Another approach : individual "piezo stacks" with flexures in a "nested design" (*Introduction to AFM by Asylum Research, Inc. (Quicktime Movie)- Pset 2*)

GENERAL COMPONENTS OF A NANOMECHANICS DEVICE



HIGH RESOLUTION FORCE SPECTROSCOPY EXPERIMENT (HRFS): RAW DATA

approaching

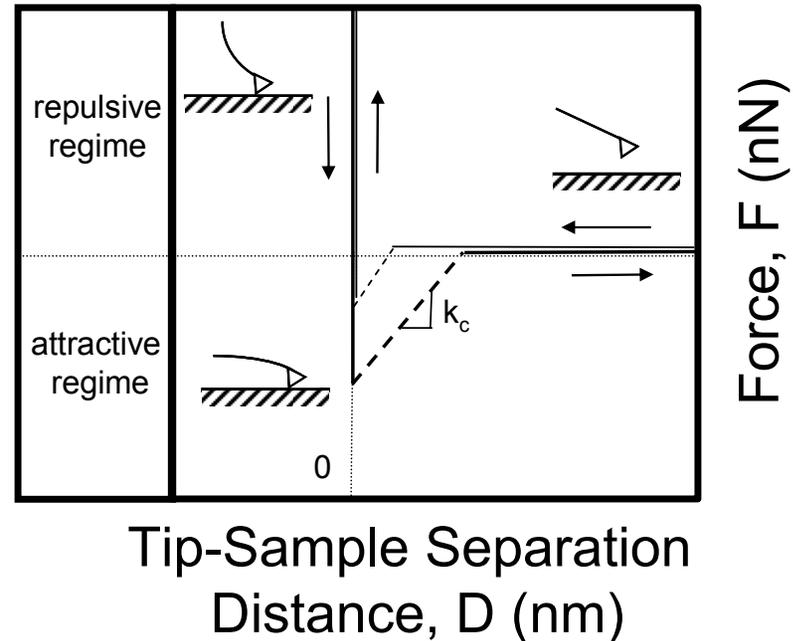
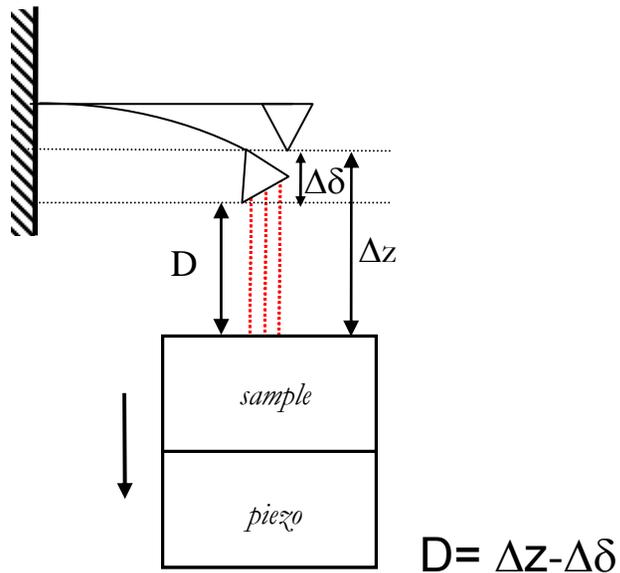


- Measure sensor output (Volts) vs. z-piezo displacement/deflection

- See animation on the MIT Server (Force curve animation from NC State).

HIGH RESOLUTION FORCE SPECTROSCOPY EXPERIMENT: CONVERTED F-D DATA

x-axis conversion



Contact vs. Noncontact region

Zero x-axis position chosen ($x=0$) : by baseline far away from sample

Zero y-axis position chosen ($D=0$) : as region of apparent infinite slope (artifact of soft spring, stiff sample)

Jump to contact region : region of mechanical instability, cantilever moving too fast to collect data, lose all data in this region

Adhesion force : maximum force needed to separate two bodies, determined by surfaces force/ intermolecular interactions; sources; hydration capillary forces in air, noncovalent interactions, polymer interactions, etc.

CHEMICAL FORCE MICROSCOPY (CFM)

Vezenov DV, Noy A, Rosznyi LF, Lieber CM. 1997. *J. Am. Chem. Soc.*

www.polymercentre.org.uk

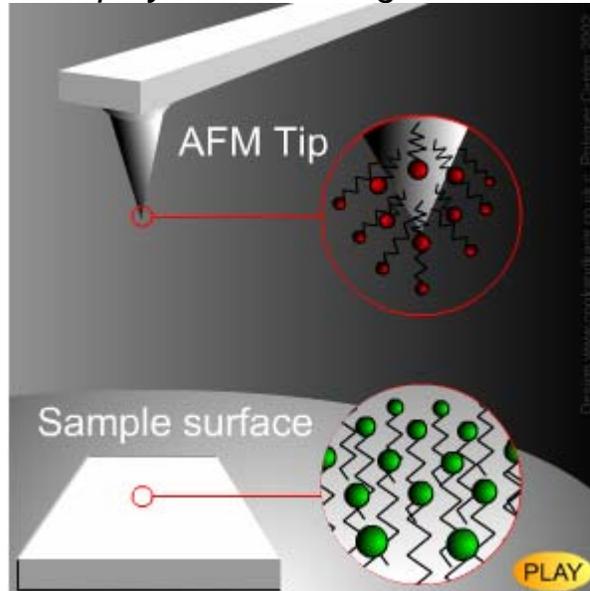


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See Vezenov DV, Noy A, Rosznyi LF, Lieber CM. 1997. *J. Am. Chem. Soc.*

Courtesy of The University of Sheffield Polymer Centre. Used with permission.

MEASURING MACROMOLECULAR ADHESION : CARTILAGE AGGREGAN

Cartilage **aggrecan** is a very unique "bottle-brush" macromolecule that is largely responsible for the mechanical properties and health of cartilage tissue in our joints.
 (*podcasts later on in the semester on this topic, unpublished data by L. Han)

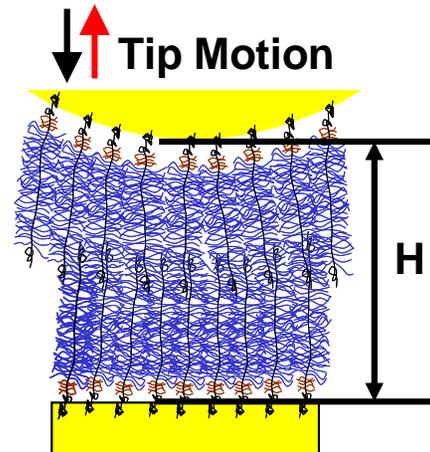
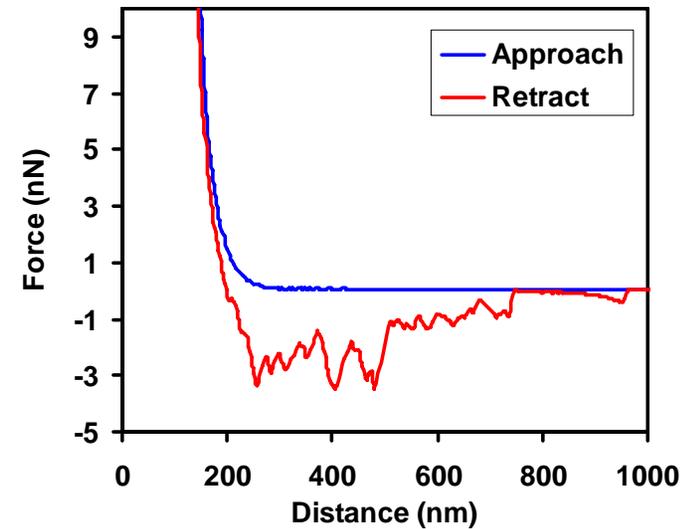
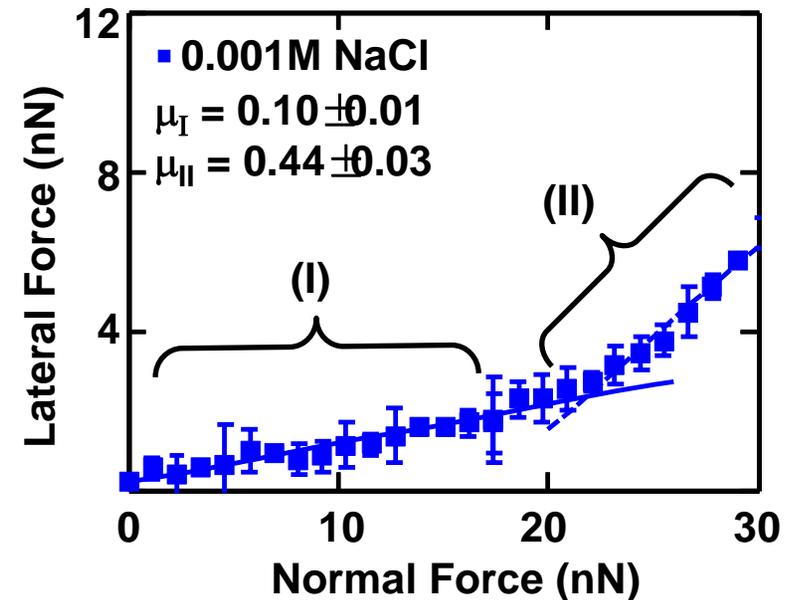
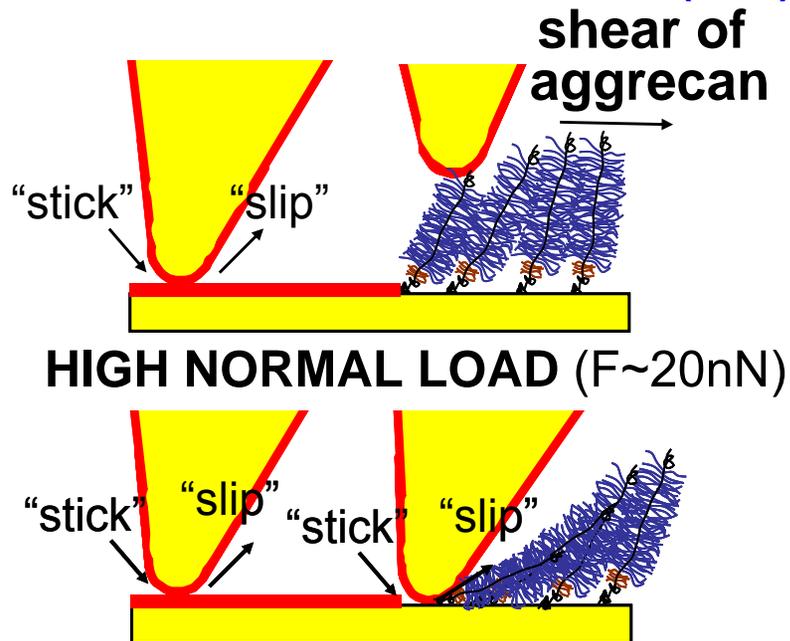


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 Diagram of cartilage aggrecan.



LATERAL FORCE MICROSCOPY (LFM)



- Measure shear / friction coefficient → nanotribology - study of friction and wear.
- Linear dependence of lateral force on normal force between OH-SAM and aggregan changed upon the point of full penetration of aggregan layer by the nanosized probe tip.
- At the same height, larger lateral forces were observed at lower IS, due to stronger shear resistance